

1. Record Nr.	UNINA9910983389103321
Autore	Peng Zhiwei
Titolo	Characterization of Minerals, Metals, and Materials 2025 : In-Situ Characterization Techniques // edited by Zhiwei Peng, Kelvin Yu Xie, Mingming Zhang, Jian Li, Bowen Li, Sergio Neves Monteiro, Rajiv Soman, Jiann-Yang Hwang, Yunus Eren Kalay, Juan P. Escobedo-Diaz, John S. Carpenter, Andrew D. Brown, Shadia Ikhmayies
Pubbl/distr/stampa	Cham : , : Springer Nature Switzerland : , : Imprint : Springer, , 2025
ISBN	9783031806803 3031806808
Edizione	[1st ed. 2025.]
Descrizione fisica	1 online resource (679 pages)
Collana	The Minerals, Metals & Materials Series, , 2367-1696
Altri autori (Persone)	XieKelvin Yu ZhangMingming LiJian LiBowen MonteiroSergio Neves SomanRajiv HwangJiann-Yang KalayYunus Eren Escobedo-DiazJuan P
Disciplina	620.112
Soggetti	Materials - Analysis Metals Mineralogy Materials science Materials Characterization Technique Metals and Alloys Materials Science
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Sommario/riassunto	The collection focuses on the advancements of characterization of minerals, metals, and materials and the applications of characterization

results on the processing of these materials. Advanced characterization methods, techniques, and new instruments are emphasized. Areas of interest include but are not limited to: Extraction and processing of various types of minerals, process-structure-property relationship of metal alloys, glasses, ceramics, polymers, composites, semiconductors, and carbon using functional and structural materials Novel methods and techniques for characterizing materials across a spectrum of systems and processes Characterization of mechanical, thermal, electrical, optical, dielectric, magnetic, physical, and other properties of metals, polymers, and ceramics including battery materials Characterization of structural, morphological, and topographical natures of materials at micro- and nano-scales Characterization of extraction and processing including process development and analysis Advances in instrument development for microstructure analysis and performance evaluation of materials, such as computer tomography (CT), X-ray and neutron diffraction, electron microscopy (SEM, FIB, TEM), and spectroscopy (EDS, WDS, EBSD) techniques 2D and 3D modelling for materials characterization.
